

<b>Notice of References Cited</b>	Application/Control No. 10/002,652	Applicant(s)/Patent Under Reexamination CHEN, BEN WEI	
	Examiner Rehana Perveen	Art Unit 2116	Page 1 of 1

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	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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